

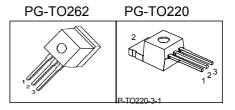
# SPP11N60S5 SPI11N60S5

#### **Cool MOS™ Power Transistor**

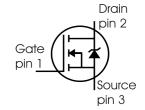
#### **Feature**

- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme dv/dt rated
- Ultra low effective capacitances
- Improved transconductance
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>0)</sup> for target applications

$V_{DS}$	600	٧
R <sub>DS(on)</sub>	0.38	Ω
I <sub>D</sub>	11	Α



Туре	Package	Ordering Code	Marking
SPP11N60S5	PG-TO220	Q67040-S4198	11N60S5
SPI11N60S5	PG-TO262	Q67040-S4338	11N60S5



#### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Continuous drain current	$I_{D}$		А
<i>T</i> <sub>C</sub> = 25 °C		11	
T <sub>C</sub> = 100 °C		7	
Pulsed drain current, $t_p$ limited by $T_{jmax}$	I <sub>D puls</sub>	22	
Avalanche energy, single pulse	E <sub>AS</sub>	340	mJ
$I_{\rm D}$ = 5.5 A, $V_{\rm DD}$ = 50 V			
Avalanche energy, repetitive $t_{AR}$ limited by $T_{imax}^{1}$	E <sub>AR</sub>	0.6	
$I_{\rm D}$ = 11 A, $V_{\rm DD}$ = 50 V			
Avalanche current, repetitive $t_{AR}$ limited by $T_{jmax}$	I <sub>AR</sub>	11	А
Gate source voltage	$V_{\rm GS}$	±20	V
Gate source voltage AC (f >1Hz)	$V_{\rm GS}$	±30	
Power dissipation, $T_C = 25^{\circ}C$	P <sub>tot</sub>	125	W
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55 +150	°C



#### **Maximum Ratings**

Parameter	Symbol	Value	Unit
Drain Source voltage slope	dv/dt	20	V/ns
$V_{\rm DS}$ = 480 V, $I_{\rm D}$ = 11 A, $T_{\rm j}$ = 125 °C			

### **Thermal Characteristics**

Parameter	Symbol	Values			Unit
		min.	typ.	max.	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	1	K/W
Thermal resistance, junction - ambient, leaded	R <sub>thJA</sub>	-	-	62	
SMD version, device on PCB:	$R_{thJA}$				
@ min. footprint		-	-	62	
@ 6 cm <sup>2</sup> cooling area <sup>2)</sup>		-	35	-	
Soldering temperature, wavesoldering	T <sub>sold</sub>	-	-	260	°C
1.6 mm (0.063 in.) from case for 10s					

# Electrical Characteristics, at Tj=25°C unless otherwise specified

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =0.25mA	600	-	-	V
Drain-Source avalanche	V <sub>(BR)DS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =11A	-	700	-	
breakdown voltage	, ,					
Gate threshold voltage	V <sub>GS(th)</sub>	$I_{\rm D}$ =500 $\mu{\rm A}, V_{\rm GS} = V_{\rm DS}$	3.5	4.5	5.5	
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V,				μΑ
		<i>T</i> <sub>j</sub> =25°C,	-	-	25	
		<i>T</i> <sub>j</sub> =150°C	-	-	250	
Gate-source leakage current	I <sub>GSS</sub>	<i>V</i> <sub>GS</sub> =20V, <i>V</i> <sub>DS</sub> =0V	-	-	100	nA
Drain-source on-state resistance	R <sub>DS(on)</sub>	<i>V</i> <sub>GS</sub> =10V, <i>I</i> <sub>D</sub> =7A,				Ω
	, ,	<i>T</i> <sub>j</sub> =25°C	-	0.34	0.38	
		<i>T</i> <sub>j</sub> =150°C	-	0.92	-	
Gate input resistance	$R_{G}$	f=1MHz, open Drain	-	29	-	



**Electrical Characteristics** , at  $T_i$  = 25 °C, unless otherwise specified

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Characteristics	•	•		•	,	
Transconductance	$g_{fs}$	$V_{\rm DS} \ge 2*I_{\rm D}*R_{\rm DS(on)max},$ $I_{\rm D} = 7A$	-	6	-	S
Input capacitance	$C_{iss}$	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V,	-	1460	-	pF
Output capacitance	$C_{oss}$	<i>f</i> =1MHz	-	610	-	
Reverse transfer capacitance	$C_{rss}$		-	21	-	
Effective output capacitance,3)	C <sub>o(er)</sub>	V <sub>GS</sub> =0V,	-	45	-	pF
energy related		V <sub>DS</sub> =0V to 480V				
Effective output capacitance,4)	C <sub>o(tr)</sub>		-	85	-	
time related						
Turn-on delay time	$t_{d(on)}$	V <sub>DD</sub> =350V, V <sub>GS</sub> =0/10V,	-	130	-	ns
Rise time	$t_{r}$	I <sub>D</sub> =11A, R <sub>G</sub> =6.8Ω	-	35	-	
Turn-off delay time	t <sub>d(off)</sub>		-	150	225	
Fall time	$t_{f}$		-	20	30	

#### **Gate Charge Characteristics**

Gate to source charge	Q <sub>gs</sub>	V <sub>DD</sub> =350V, I <sub>D</sub> =11A	-	10.5	-	nC
Gate to drain charge	$Q_{gd}$		-	24	-	
Gate charge total	$Q_g$	V <sub>DD</sub> =350V, I <sub>D</sub> =11A,	-	41.5	54	
		V <sub>GS</sub> =0 to 10V				
Gate plateau voltage	V <sub>(plateau)</sub>	V <sub>DD</sub> =350V, I <sub>D</sub> =11A	-	8	-	V

<sup>&</sup>lt;sup>0</sup>J-STD20 and JESD22

<sup>&</sup>lt;sup>1</sup>Repetitve avalanche causes additional power losses that can be calculated as  $P_{\text{AV}} = E_{\text{AR}} * f$ .

 $<sup>^2\</sup>text{Device}$  on  $40\text{mm}^*40\text{mm}^*1.5\text{mm}$  epoxy PCB FR4 with  $6\text{cm}^2$  (one layer, 70  $\mu\text{m}$  thick) copper area for drain connection. PCB is vertical without blown air.

 $<sup>^3</sup>C_{\rm o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{\rm oss}$  while  $V_{\rm DS}$  is rising from 0 to 80%  $V_{\rm DSS}$ .

 $<sup>^4</sup>C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

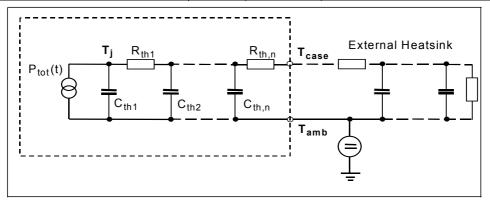


**Electrical Characteristics**, at  $T_j = 25$  °C, unless otherwise specified

Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Inverse diode continuous	IS	<i>T</i> <sub>C</sub> =25°C	-	-	11	Α
forward current						
Inverse diode direct current,	I <sub>SM</sub>		-	-	22	
pulsed						
Inverse diode forward voltage	$V_{\mathrm{SD}}$	V <sub>GS</sub> =0V, I <sub>F</sub> =I <sub>S</sub>	-	1	1.2	V
Reverse recovery time	t <sub>rr</sub>	V <sub>R</sub> =350V, I <sub>F</sub> =I <sub>S</sub> ,	-	650	1105	ns
Reverse recovery charge	Q <sub>rr</sub>	d <i>i<sub>F</sub></i> /d <i>t</i> =100A/µs	-	7.9	-	μC

**Typical Transient Thermal Characteristics** 

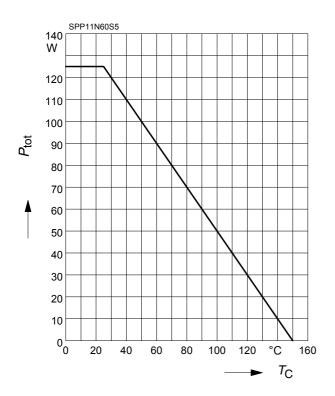
Symbol	Value	Unit	Symbol	Value	Unit
	typ.			typ.	
Thermal resistance		Thermal capacitance			
R <sub>th1</sub>	0.015	K/W	C <sub>th1</sub>	0.0001878	Ws/K
R <sub>th2</sub>	0.03		C <sub>th2</sub>	0.0007106	
R <sub>th3</sub>	0.056		C <sub>th3</sub>	0.000988	
R <sub>th4</sub>	0.197		C <sub>th4</sub>	0.002791	
R <sub>th5</sub>	0.216		C <sub>th5</sub>	0.007285	
R <sub>th6</sub>	0.083		C <sub>th6</sub>	0.063	





#### 1 Power dissipation

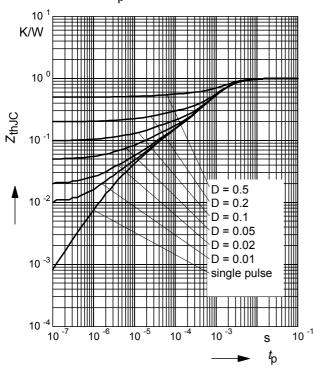
$$P_{\text{tot}} = f(T_{\text{C}})$$



# 3 Transient thermal impedance

$$Z_{\text{thJC}} = f(t_{\text{p}})$$

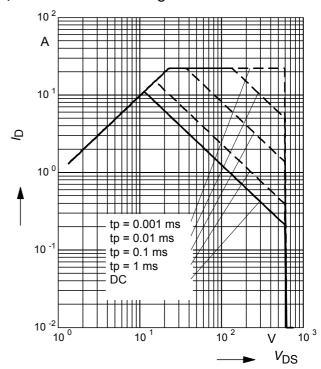
parameter:  $D = t_D/T$ 



# 2 Safe operating area

$$I_{\mathsf{D}} = f(V_{\mathsf{DS}})$$

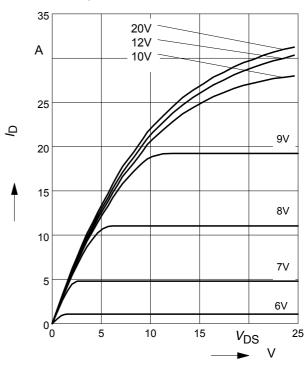
parameter : D = 0 ,  $T_C = 25$ °C



# 4 Typ. output characteristic

 $I_{D} = f(V_{DS}); T_{i} = 25^{\circ}C$ 

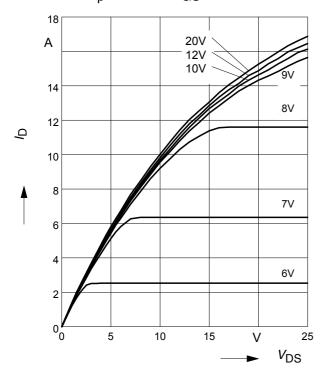
parameter:  $t_p$  = 10  $\mu$ s,  $V_{GS}$ 





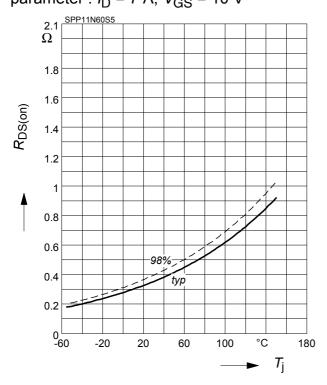
# 5 Typ. output characteristic

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 150 ^{\circ} {\rm C}$ parameter:  $t_{\rm p} = 10 \ \mu {\rm s}, \ V_{\rm GS}$ 



#### 7 Drain-source on-state resistance

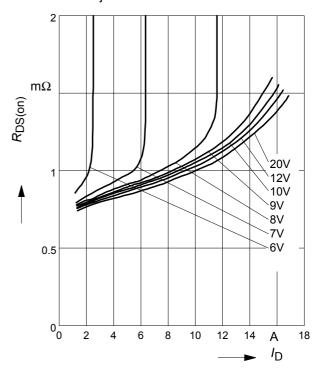
 $R_{\mathrm{DS(on)}} = f(T_{\mathrm{j}})$ parameter :  $I_{\mathrm{D}} = 7 \,\mathrm{A}, \, V_{\mathrm{GS}} = 10 \,\mathrm{V}$ 



# 6 Typ. drain-source on resistance

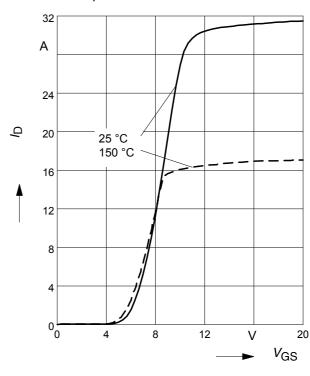
 $R_{DS(on)} = f(I_D)$ 

parameter:  $T_i$ =150°C,  $V_{GS}$ 



### 8 Typ. transfer characteristics

 $I_{\rm D}$ = f (  $V_{\rm GS}$  );  $V_{\rm DS}$  $\geq$  2 x  $I_{\rm D}$  x  $R_{\rm DS(on)max}$  parameter:  $t_{\rm p}$  = 10  $\mu$ s

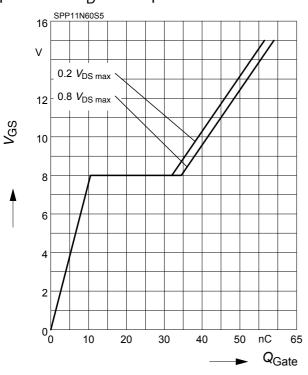




### 9 Typ. gate charge

 $V_{GS} = f (Q_{Gate})$ 

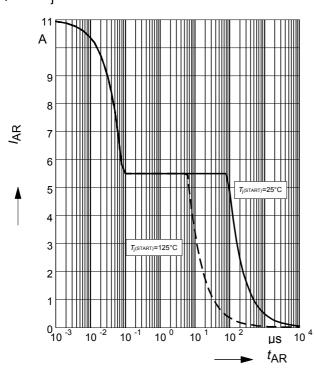
parameter:  $I_D$  = 11 A pulsed



# 11 Avalanche SOA

 $I_{AR} = f(t_{AR})$ 

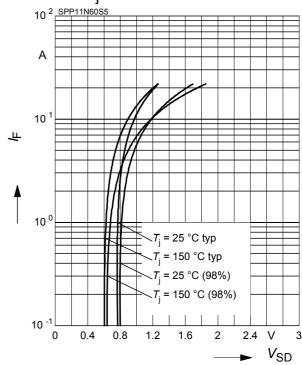
par.:  $T_j \le 150 \, ^{\circ}\text{C}$ 



### 10 Forward characteristics of body diode

$$I_{\mathsf{F}} = f(\mathsf{V}_{\mathsf{SD}})$$

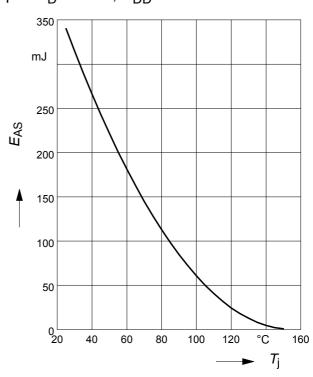
parameter:  $T_{j}$  , tp = 10  $\mu s$ 



#### 12 Avalanche energy

$$E_{AS} = f(T_i)$$

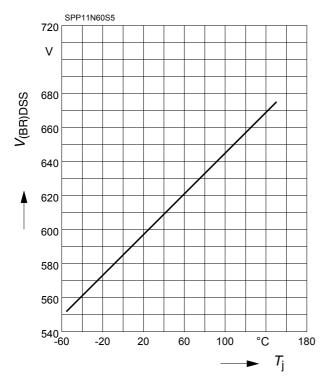
par.:  $I_D$  = 5.5 A,  $V_{DD}$  = 50 V





#### 13 Drain-source breakdown voltage

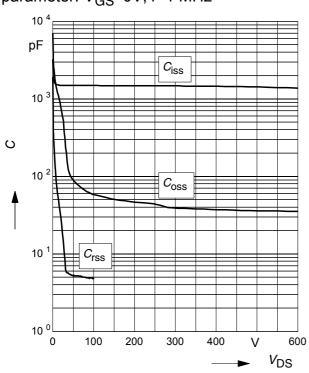
$$V_{(BR)DSS} = f(T_j)$$



# 15 Typ. capacitances

$$C = f(V_{DS})$$

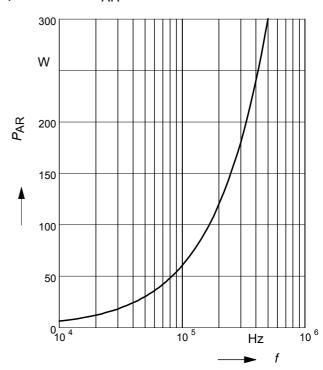
parameter:  $V_{GS}$ =0V, f=1 MHz



#### 14 Avalanche power losses

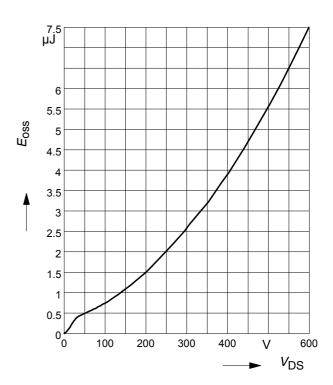
$$P_{AR} = f(f)$$

parameter: EAR=0.6mJ



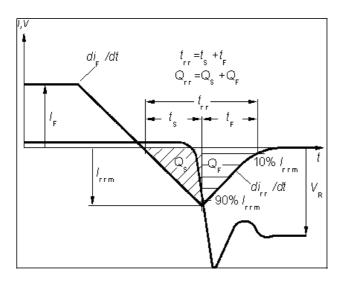
# 16 Typ. $C_{\rm OSS}$ stored energy

$$E_{\text{oss}} = f(V_{\text{DS}})$$



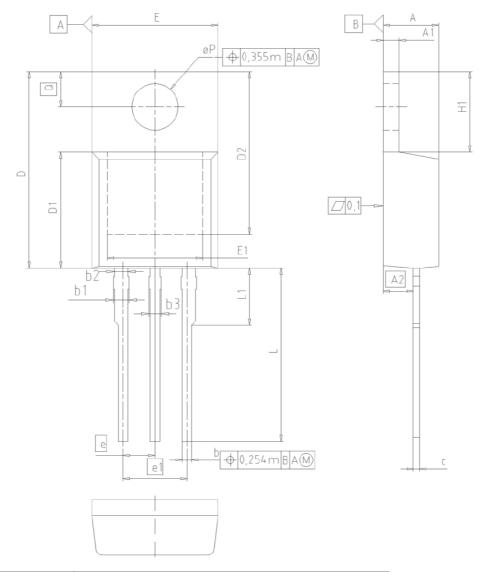


# Definition of diodes switching characteristics





# PG-TO220-3-1, PG-TO220-3-21

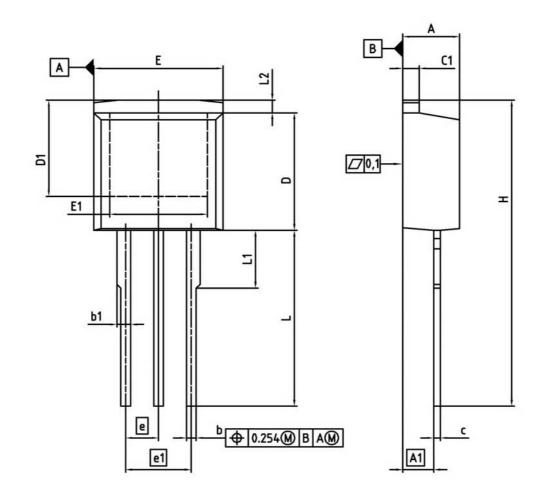


DIM	MILLIN	METERS	INC	IES
DIN	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	1.17	1.40	0.046	0.055
A2	2.15	2.72	0.085	0.107
b	0.65	0.86	0.026	0.034
<b>b</b> 1	0.95	1.40	0.037	0.055
b2	0.95	1.15	0.037	0.045
b3	0.65	1.15	0.026	0.045
С	0.33	0.60	0.013	0.024
D	14.81	15.95	0.583	0.628
D1	8.51	9.45	0.335	0.372
D2	12.19	13.10	0.480	0.516
E	9.70	10.36	0.382	0.408
E1	6.50	8.60	0.256	0.339
e	2.	54	0.1	00
e1	5.	08	0.2	200
N		3		3
H1	5.90	6.90	0.232	0.272
L	13.00	14.00	0.512	0.551
L1	-	4.80	-	0.189
øΡ	3.60	3.89	0.142	0.153
Q	2.60	3.00	0.102	0.118

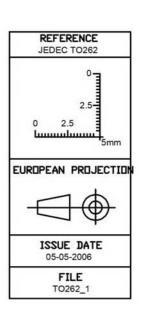
<b>DOCUMENT NO.</b> Z8B00003318		
SCALE	0	
0 2.5	2.5 5mm	
EUROPEAN P	ROJECTION	
ISSUE DATE 23-08-2007		
REVISION 05		



# PG-TO262-3-1, PG-TO262-3-21 (I<sup>2</sup>-PAK)



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	2.150	2.718	0.085	0.107
b	0.650	0.864	0.026	0.034
b1	0.635	1.400	0.025	0.055
C	0.330	0.600	0.013	0.024
c1	1.170	1.400	0.046	0.055
D	8.509	9.450	0.335	0.372
D1	6.900		0.272	
Ε	9.700	10.363	0.382	0.408
E1	6.500	8.600	0.256	0.339
6	2.540		0.100	
e1	5.080		0.200	
N	3		3	
L	13.000	14.000	0.512	0.551
L1	151	4.800	-	0.189
12		1 727		0.068





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